ON Semiconductor®



Title of Change:	Moisture Sensitivity Level (MSL) rating conversion of NCP1611 device family from MSL3 to MSL2.
Effective date:	20 September 2017
Contact information:	Contact your local ON Semiconductor Sales Office or < <u>Jiri.Konarik@onsemi.com</u> >
Type of notification:	ON Semiconductor will consider this change accepted.
Change category:	□ Wafer Fab Change □ Assembly Change □ Test Change ☑ Other - <u>Packaging/Labelling</u>
Change Sub-Category(s):	
Sites Affected:	plicable ON Semiconductor site(s) : ON Carmona, Philippines DN Carmona, Philippines
Description and Purpose:	
The Product Bulletin is to notify customer that the Moisture Sensitivity Level (MSL) rating for NCP1611ADR2G and NCP1611BDR2G products, in our SOIC-8 package, will be updated from MSL3/260 to MSL2/260.	
There is no change in the BOM or packaging, only the label will change to indicate an MSL2 rating.	
Effective 15-September-2017 the label will change from MLS3/260 to MSL2/260.	
The reliability report qualifying this change is available upon request. Please send your request to < <u>liri.Konarik@onsemi.com></u> to receive a copy.	
List of Affected Standard Parts:	
NCP1611ADR2G NCP1611BDR2G	